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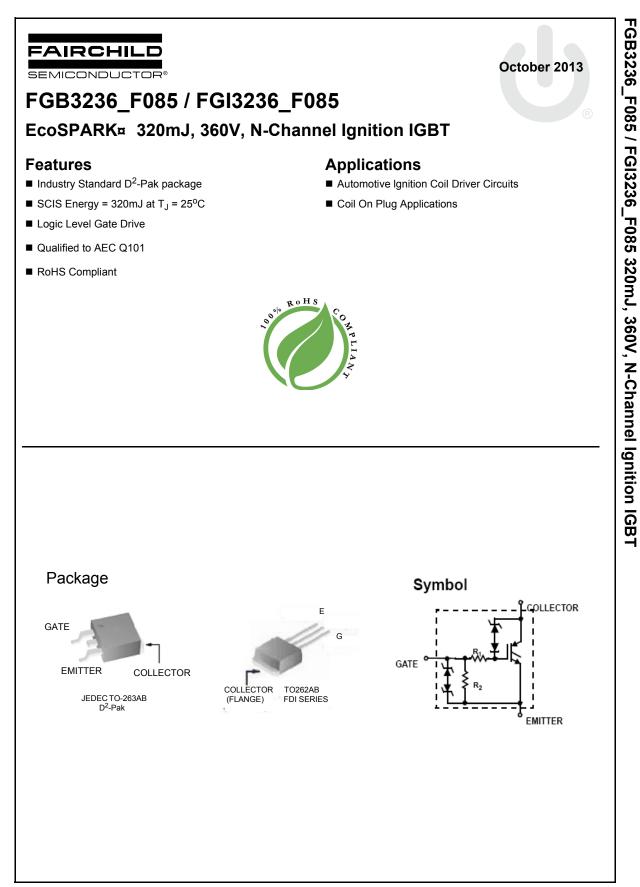


## **ON Semiconductor**®

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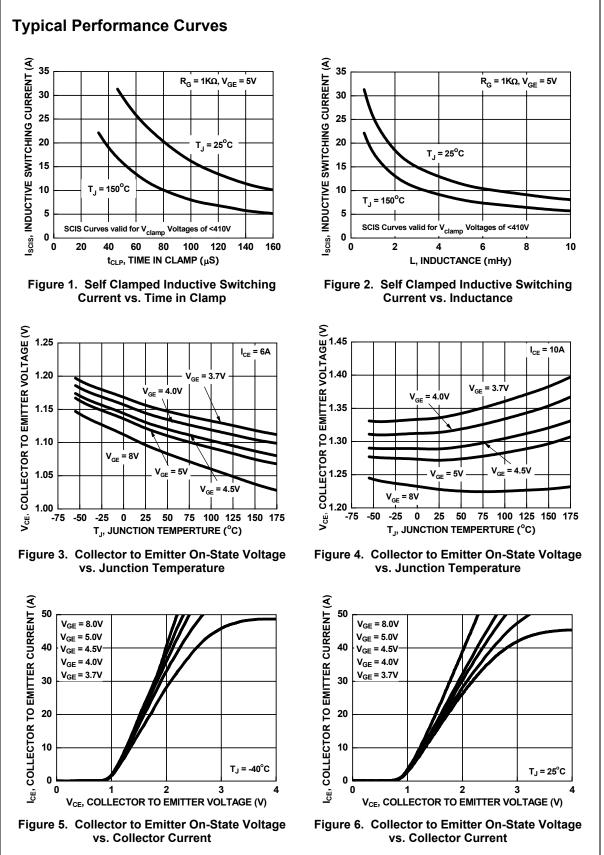
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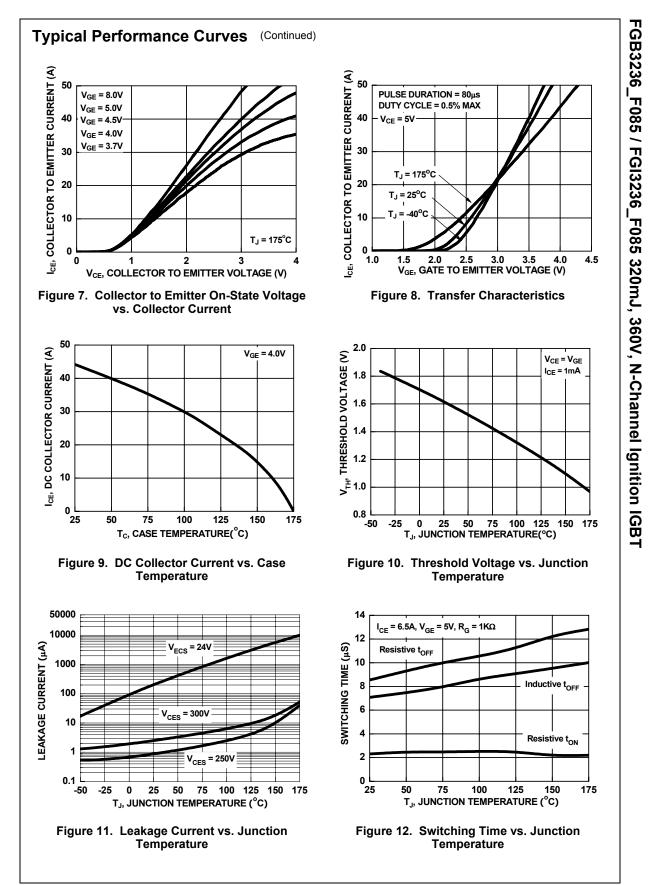


| Symbol  |   | Parameter   |   |  |   |   | Ratings  |   | Unit   |  |
|---|---|---|---|--|---|---|--|---|--|--|
| V <sub>CER</sub>  | Collector to Emitter Breakdown Voltage  |   |   | (I <sub>C</sub> = 1mA  | )   |   |  | 360   |  | V                                      |
| V <sub>ECS</sub>  | Emitter to Collector Voltage - Reverse B  |   |   |  |   |   |  | 24  |  | V                                      |
| SCIS25  | Self Clamping Inductive Switching Energy ( $I_{SCIS}$ = 14.7A, L = 3.0mHy, $T_{J}$ = 25°C)  |   |   |  |   | 320   |  | mJ  |  |  |
| SCIS150   | Self Clam   |   |   |  |   |   | ;)   | 160   |  | mJ                                     |
| 25  | Collector Current Continuous, at V <sub>GE</sub> =  |   |   | 4.0V, T <sub>C</sub> =   | 25°C  |   |  | 44  |  | Α                                      |
| 110   | Collector Current Continuous, at $V_{GE}$ =   |   |   | 4.0V, T <sub>C</sub> =   | 110°C   |   |  | 27  |  | Α                                      |
| GEM   | Gate to Emitter Voltage Continuous  |   |   |  |   |   |  | ±10   |  | V                                      |
| D   |   | sipation Total, at T <sub>C</sub>   |   |  |   |   |  | 187   |  | W                                      |
|   | Power Dissipation Derating, for $T_C > 25^{\circ}C$   |   |   |  |   | 1.25  |  |   | W/ºC   |  |
| J   | Operating Junction Temperature Range  |   |   |  |   |   | -40 to +175  |   | °C<br>°C   |  |
| STG   |   | unction Temperature   |   |  |   |   | -4   | -40 to +175   |  |  |
| L   |   | Temp. for Solderin  |   |  |   | S)  |  | 300   |  |  |
| PKG   |   | Temp. for Solderin  | • • •   |  | 10s)  |   |  | 260   |  | °C                                     |
| SD  | Electrosta  | tic Discharge Voltag  | je at100ph  | -, 1500Ω   |   |   |  | 4   |  | kV                                     |
| Packa   | ige Mar   | king and Or   | dering  | Inform   | nation  |   |  |   |  |  |
| Device  | Marking   | Device  | Packa   | ge   | Reel Size   | Tape W  | dth  | Q   | uantit   | y                                      |
| FG  | B3236   | FGB3236_F085  | TO26  | 3  | 330mm   | 330mm 24mm  |  | 8   |  | S                                      |
| FG  | 13236   | FGI3236_F085  | TO26  | 2  | Tube  | NA  |  | 50 units  |  | ;                                      |
|   | -   | aracteristics   | T <sub>A</sub> = 25°  | C unless c   |   |   |  | -   |  | I                                      |
| Symbol  |   | Parameter   | T <sub>A</sub> = 25°  | C unless o   | therwise noted<br>Test Condi  | tions   | Min  | Тур   | Max  | Units                                  |
| Symbol  |   |   | T <sub>A</sub> = 25°  | C unless o   |   | tions   | Min  | Тур   | Max  | Units                                  |
| Symbol<br>Off Sta   | te Chara  | Parameter<br>cteristics   |   | I <sub>CE</sub> = 2mA  | Test Condi<br>A, V <sub>GE</sub> = 0,   | tions   |  |   |  |  |
| Symbol<br>Off Sta   | te Chara  | Parameter   |   | I <sub>CE</sub> = 2mA<br>R <sub>GE</sub> = 1K  | <b>Test Condi</b><br>A, V <sub>GE</sub> = 0,<br>Ω, See Fig. 15  | tions   | Min<br>330   | <b>Тур</b><br>363   | <b>Max</b><br>390  | Units                                  |
| Symbol<br>Off Sta   | te Chara  | Parameter<br>cteristics   |   | $I_{CE} = 2mA$<br>$R_{GE} = 1K$<br>$T_J = -40$ to  | <b>Test Condi</b><br>A, V <sub>GE</sub> = 0,<br>Ω, See Fig. 15<br>o 150°C   | tions   |  |   |  |  |
| Symbol<br>Dff Sta<br><sup>BV</sup> CER  | te Chara  | Parameter<br>cteristics<br>o Emitter Breakdow   | n Voltage   | $I_{CE} = 2mA$<br>$R_{GE} = 1K$<br>$T_J = -40 ta$<br>$I_{CE} = 10m$  | <b>Test Condi</b><br>A, V <sub>GE</sub> = 0,<br>Ω, See Fig. 15  | tions   | 330  | 363   | 390  | V                                      |
| Symbol<br>Dff Sta<br><sup>BV</sup> CER  | te Chara  | Parameter<br>cteristics   | n Voltage   | $I_{CE} = 2mA$ $R_{GE} = 1K$ $T_{J} = -40 \text{ tr}$ $I_{CE} = 10m$ $R_{GE} = 0,$   | Test Condi<br>$\Delta$ , $V_{GE} = 0$ ,<br>$\Omega$ , See Fig. 15<br>$D = 150^{\circ}C$<br>$\Delta$ , $V_{GE} = 0V$ ,   | tions   |  |   |  |  |
| Symbol<br>Off Sta<br><sup>3V</sup> CER<br>3V <sub>CES</sub>   | te Chara<br>Collector t<br>Collector t  | Parameter<br>cteristics<br>o Emitter Breakdow<br>o Emitter Breakdow   | n Voltage<br>n Voltage  | $I_{CE} = 2mA$ $R_{GE} = 1K$ $T_{J} = -40 \text{ tr}$ $I_{CE} = 10m$ $R_{GE} = 0,$ $T_{J} = -40 \text{ tr}$  | Test Condi<br>$A, V_{GE} = 0,$<br>Ω, See Fig. 15<br>$0.150^{\circ}C$<br>$A, V_{GE} = 0V,$<br>$D, V_{GE} = 0V,$<br>$D, 150^{\circ}C$   | tions   | 330<br>350   | 363   | 390  | v<br>v                                 |
| Symbol<br>Off Sta<br><sup>3V</sup> CER<br><sup>3V</sup> CES   | te Chara<br>Collector t<br>Collector t  | Parameter<br>cteristics<br>o Emitter Breakdow   | n Voltage<br>n Voltage  | $I_{CE} = 2mA$ $R_{GE} = 1K$ $T_{J} = -40 \text{ tr}$ $I_{CE} = 10m$ $R_{GE} = 0,$ $T_{J} = -40 \text{ tr}$  | Test Condi<br>A, V <sub>GE</sub> = 0,<br>Ω, See Fig. 15<br>$0.150^{\circ}$ C<br>A, V <sub>GE</sub> = 0V,<br>$0.150^{\circ}$ C<br>nA, V <sub>GE</sub> = 0V,  | tions   | 330  | 363   | 390  | V                                      |
| Symbol<br>Dff Sta<br>BV <sub>CER</sub><br>BV <sub>CES</sub><br>BV <sub>ECS</sub>  | te Chara<br>Collector t<br>Collector t<br>Emitter to  | Parameter<br>cteristics<br>o Emitter Breakdow<br>o Emitter Breakdow   | n Voltage<br>n Voltage<br>n Voltage                                 | $I_{CE} = 2mA$<br>$R_{GE} = 1K$<br>$T_{J} = -40 \text{ tr}$<br>$I_{CE} = 10m$<br>$R_{GE} = 0,$<br>$T_{J} = -40 \text{ tr}$<br>$I_{CE} = -75r$  | Test Condi<br>$A, V_{GE} = 0,$<br>$\Omega, See Fig. 15$<br>$b 150^{\circ}C$<br>$A, V_{GE} = 0V,$<br>$b 150^{\circ}C$<br>$nA, V_{GE} = 0V,$<br>c   |   | 330<br>350   | 363   | 390  | v<br>v                                 |
| Symbol<br>Dff Sta<br>3V <sub>CER</sub><br>3V <sub>CES</sub><br>3V <sub>ECS</sub><br>3V <sub>GES</sub>   | te Chara<br>Collector t<br>Collector t<br>Emitter to<br>Gate to Er  | Parameter<br>cteristics<br>o Emitter Breakdow<br>o Emitter Breakdow<br>Collector Breakdow<br>nitter Breakdown Vo  | n Voltage<br>n Voltage<br>n Voltage<br>bltage                       | $I_{CE} = 2mA$ $R_{GE} = 1K$ $T_{J} = -40 tr$ $R_{GE} = 0,$ $T_{J} = -40 tr$ $I_{CE} = -75r$ $T_{C} = 25°C$ $I_{GES} = \pm 2$ $V_{CES} = 25$   | Test Condi<br>A, $V_{GE} = 0$ ,<br>$\Omega$ , See Fig. 15<br>$D = 150^{\circ}C$<br>$D = 150^{\circ}C$<br>$D = 150^{\circ}C$<br>$D = 150^{\circ}C$<br>$D = 150^{\circ}C$<br>D = 0V,<br>D = 0,<br>D = 0V,<br>D = | T <sub>C</sub> = 25°C   | 330<br>350<br>30   | 363<br>378<br>-   | 390  | v<br>v<br>v                            |
| Symbol<br>Dff Sta<br>BV <sub>CER</sub><br>BV <sub>CES</sub><br>BV <sub>ECS</sub><br>BV <sub>GES</sub>   | te Chara<br>Collector t<br>Collector t<br>Emitter to<br>Gate to Er  | Parameter<br>cteristics<br>o Emitter Breakdow<br>o Emitter Breakdow<br>Collector Breakdow   | n Voltage<br>n Voltage<br>n Voltage<br>bltage                       | $I_{CE} = 2mA$ $R_{GE} = 1K$ $T_{J} = -40 \text{ tr}$ $R_{GE} = 0,$ $T_{J} = -40 \text{ tr}$ $I_{CE} = -75r$ $T_{C} = 25^{\circ}C$ $I_{GES} = \pm 2$ $V_{CES} = 25$ See Fig. 1   | Test Condi<br>A, V <sub>GE</sub> = 0,<br>Ω, See Fig. 15<br>b 150°C<br>A, V <sub>GE</sub> = 0V,<br>b 150°C<br>mA, V <sub>GE</sub> = 0V,<br>c<br>mA<br>50V,<br>11   | $\frac{T_{C} = 25^{\circ}C}{T_{C} = 150^{\circ}C}$  | 330<br>350<br>30<br>±12                                    | 363<br>378<br>-<br>±14                                    | 390<br>410<br>-  | V<br>V<br>V                            |
| Symbol<br>Off Sta<br>3V <sub>CER</sub><br>3V <sub>CES</sub><br>3V <sub>ECS</sub><br>3V <sub>GES</sub><br>CES  | te Chara<br>Collector t<br>Collector t<br>Emitter to<br>Gate to Er<br>Collector t   | Parameter<br>cteristics<br>o Emitter Breakdow<br>o Emitter Breakdow<br>Collector Breakdow<br>nitter Breakdown Vo<br>o Emitter Leakage (   | n Voltage<br>n Voltage<br>n Voltage<br>Ditage<br>Current            | $I_{CE} = 2mA$ $R_{GE} = 1K$ $T_{J} = -40 \text{ to}$ $I_{CE} = 10m$ $R_{GE} = 0,$ $T_{J} = -40 \text{ to}$ $I_{CE} = -75r$ $T_{C} = 25^{\circ}C$ $I_{GES} = \pm 2$ $V_{CES} = 25$ See Fig. 1 $V_{EC} = 24V$   | Test Condi<br>A, V <sub>GE</sub> = 0,<br>Ω, See Fig. 15<br>b 150°C<br>A, V <sub>GE</sub> = 0V,<br>b 150°C<br>mA, V <sub>GE</sub> = 0V,<br>c<br>mA<br>50V,<br>11<br>/,   | $\frac{T_{C} = 25^{\circ}C}{T_{C} = 150^{\circ}C}$ $T_{C} = 25^{\circ}C$  | 330<br>350<br>30<br>±12                                    | 363<br>378<br>-<br>±14                                    | 390<br>410<br>-<br>25                                    | V<br>V<br>V<br>µA<br>mA                |
| Symbol<br>Off Sta<br>3V <sub>CER</sub><br>3V <sub>ECS</sub><br>3V <sub>GES</sub><br>ces<br>ecs  | te Chara<br>Collector t<br>Collector t<br>Emitter to<br>Gate to Er<br>Collector t<br>Emitter to   | Parameter<br>cteristics<br>o Emitter Breakdow<br>o Emitter Breakdow<br>Collector Breakdow<br>nitter Breakdown Vo<br>o Emitter Leakage (<br>Collector Leakage (  | n Voltage<br>n Voltage<br>n Voltage<br>Ditage<br>Current            | $I_{CE} = 2mA$ $R_{GE} = 1K$ $T_{J} = -40 \text{ tr}$ $R_{GE} = 0,$ $T_{J} = -40 \text{ tr}$ $I_{CE} = -75r$ $T_{C} = 25^{\circ}C$ $I_{GES} = \pm 2$ $V_{CES} = 25$ See Fig. 1   | Test Condi<br>A, V <sub>GE</sub> = 0,<br>Ω, See Fig. 15<br>b 150°C<br>A, V <sub>GE</sub> = 0V,<br>b 150°C<br>mA, V <sub>GE</sub> = 0V,<br>c<br>mA<br>50V,<br>11<br>/,   | $\frac{T_{C} = 25^{\circ}C}{T_{C} = 150^{\circ}C}$  | 330<br>350<br>30<br>±12                                    | 363<br>378<br>-<br>±14<br>-<br>-<br>-                     | 390<br>410<br>-<br>25<br>1                               | ν<br>ν<br>ν<br>ν                       |
| Symbol<br>Dff Sta<br>3V <sub>CER</sub><br>3V <sub>CES</sub><br>3V <sub>ECS</sub><br>3V <sub>GES</sub><br>ces<br>ecs<br>R <sub>1</sub>                                       | te Chara<br>Collector t<br>Collector t<br>Emitter to<br>Gate to Er<br>Collector t<br>Emitter to<br>Series Ga  | Parameter<br>cteristics<br>o Emitter Breakdow<br>o Emitter Breakdow<br>Collector Breakdow<br>nitter Breakdown Vo<br>o Emitter Leakage (<br>Collector Leakage (<br>te Resistance   | n Voltage<br>n Voltage<br>n Voltage<br>Ditage<br>Current            | $I_{CE} = 2mA$ $R_{GE} = 1K$ $T_{J} = -40 \text{ to}$ $I_{CE} = 10m$ $R_{GE} = 0,$ $T_{J} = -40 \text{ to}$ $I_{CE} = -75r$ $T_{C} = 25^{\circ}C$ $I_{GES} = \pm 2$ $V_{CES} = 25$ See Fig. 1 $V_{EC} = 24V$   | Test Condi<br>A, V <sub>GE</sub> = 0,<br>Ω, See Fig. 15<br>b 150°C<br>A, V <sub>GE</sub> = 0V,<br>b 150°C<br>mA, V <sub>GE</sub> = 0V,<br>c<br>mA<br>50V,<br>11<br>/,   | $\frac{T_{C} = 25^{\circ}C}{T_{C} = 150^{\circ}C}$ $T_{C} = 25^{\circ}C$  | 330<br>350<br>30<br>±12<br>-<br>-<br>-<br>-<br>-<br>-<br>- | 363<br>378<br>-<br>±14                                    | 390<br>410<br>-<br>25<br>1<br>1<br>40<br>-               | V<br>V<br>V<br>µA<br>mA                |
| Symbol<br>Dff Sta<br>3V <sub>CER</sub><br>3V <sub>CES</sub><br>3V <sub>ECS</sub><br>3V <sub>GES</sub><br>ces<br>ecs<br>R <sub>1</sub>                                       | te Chara<br>Collector t<br>Collector t<br>Emitter to<br>Gate to Er<br>Collector t<br>Emitter to<br>Series Ga  | Parameter<br>cteristics<br>o Emitter Breakdow<br>o Emitter Breakdow<br>Collector Breakdow<br>nitter Breakdown Vo<br>o Emitter Leakage (<br>Collector Leakage (  | n Voltage<br>n Voltage<br>n Voltage<br>Ditage<br>Current            | $I_{CE} = 2mA$ $R_{GE} = 1K$ $T_{J} = -40 \text{ to}$ $I_{CE} = 10m$ $R_{GE} = 0,$ $T_{J} = -40 \text{ to}$ $I_{CE} = -75r$ $T_{C} = 25^{\circ}C$ $I_{GES} = \pm 2$ $V_{CES} = 25$ See Fig. 1 $V_{EC} = 24V$   | Test Condi<br>A, V <sub>GE</sub> = 0,<br>Ω, See Fig. 15<br>b 150°C<br>A, V <sub>GE</sub> = 0V,<br>b 150°C<br>mA, V <sub>GE</sub> = 0V,<br>c<br>mA<br>50V,<br>11<br>/,   | $\frac{T_{C} = 25^{\circ}C}{T_{C} = 150^{\circ}C}$ $T_{C} = 25^{\circ}C$  | 330<br>350<br>30<br>±12<br>-<br>-<br>-                     | 363<br>378<br>-<br>±14<br>-<br>-<br>-                     | 390<br>410<br>-<br>25<br>1<br>1                          | V<br>V<br>V<br>µA<br>mA                |
| Symbol<br>Dff Sta<br>BV <sub>CER</sub><br>BV <sub>CES</sub><br>BV <sub>ECS</sub><br>BV <sub>GES</sub><br>Ices<br>Ices<br>Ices<br>R <sub>1</sub><br>R <sub>2</sub>           | te Chara<br>Collector t<br>Collector t<br>Emitter to<br>Gate to Er<br>Collector t<br>Emitter to<br>Series Gai<br>Gate to Er                           | Parameter<br>cteristics<br>o Emitter Breakdow<br>o Emitter Breakdow<br>Collector Breakdow<br>nitter Breakdown Vo<br>o Emitter Leakage (<br>Collector Leakage (<br>te Resistance   | n Voltage<br>n Voltage<br>n Voltage<br>Ditage<br>Current            | $I_{CE} = 2mA$ $R_{GE} = 1K$ $T_{J} = -40 \text{ to}$ $I_{CE} = 10m$ $R_{GE} = 0,$ $T_{J} = -40 \text{ to}$ $I_{CE} = -75r$ $T_{C} = 25^{\circ}C$ $I_{GES} = \pm 2$ $V_{CES} = 25$ See Fig. 1 $V_{EC} = 24V$   | Test Condi<br>A, V <sub>GE</sub> = 0,<br>Ω, See Fig. 15<br>b 150°C<br>A, V <sub>GE</sub> = 0V,<br>b 150°C<br>mA, V <sub>GE</sub> = 0V,<br>c<br>mA<br>50V,<br>11<br>/,   | $\frac{T_{C} = 25^{\circ}C}{T_{C} = 150^{\circ}C}$ $T_{C} = 25^{\circ}C$  | 330<br>350<br>30<br>±12<br>-<br>-<br>-<br>-<br>-<br>-<br>- | 363<br>378<br>-<br>±14<br>-<br>-<br>-                     | 390<br>410<br>-<br>25<br>1<br>1<br>40<br>-               | V<br>V<br>V<br>μΑ<br>mA<br>Ω           |
| Symbol<br>Dff Sta<br>BV <sub>CER</sub><br>BV <sub>CES</sub><br>BV <sub>ECS</sub><br>BV <sub>GES</sub><br>Ices<br>Ices<br>Ices<br>R <sub>1</sub><br>R <sub>2</sub><br>Dn Sta | te Chara<br>Collector t<br>Collector t<br>Emitter to<br>Gate to Er<br>Collector t<br>Emitter to<br>Series Ga<br>Gate to Er<br>te Chara                | Parameter<br>cteristics<br>o Emitter Breakdow<br>o Emitter Breakdow<br>Collector Breakdown VC<br>o Emitter Leakage (<br>Collector Leakage (<br>Collector Leakage (<br>te Resistance<br>nitter Resistance<br>cteristics  | n Voltage<br>n Voltage<br>n Voltage<br>Ditage<br>Current            | $I_{CE} = 2mA R_{GE} = 1K T_{J} = -40 tr R_{GE} = 0, T_{J} = -40 tr R_{GE} = 0, T_{J} = -40 tr R_{CE} = -75r T_{C} = 25°C I_{GES} = \pm 22 V_{CES} = 25 See Fig. 1 V_{EC} = 24 V_{See} Fig. 1$   | Test Condi         A, $V_{GE} = 0$ ,         Ω, See Fig. 15         D 150°C         IA, $V_{GE} = 0V$ ,         D 150°C         mA, $V_{GE} = 0V$ ,         D 150°C         mA, $V_{GE} = 0V$ ,         D 150°C         mA         50V,         1   | $\frac{T_{C} = 25^{\circ}C}{T_{C} = 150^{\circ}C}$ $\frac{T_{C} = 25^{\circ}C}{T_{C} = 150^{\circ}C}$   | 330<br>350<br>30<br>±12<br>-<br>-<br>-<br>-<br>10K         | 363<br>378<br>-<br>±14<br>-<br>-<br>-<br>100<br>-         | 390<br>410<br>-<br>25<br>1<br>1<br>40<br>-<br>30K        | V<br>V<br>V<br>μΑ<br>mA<br>Ω<br>Ω      |
| Symbol<br>Dff Sta<br>$3V_{CER}$<br>$3V_{CES}$<br>$3V_{ECS}$<br>$3V_{GES}$<br>ces<br>ecs<br>$R_1$<br>$R_2$   | te Chara<br>Collector t<br>Collector t<br>Emitter to<br>Gate to Er<br>Collector t<br>Emitter to<br>Series Ga<br>Gate to Er<br>te Chara                | Parameter<br>cteristics<br>o Emitter Breakdow<br>o Emitter Breakdow<br>Collector Breakdown Vo<br>o Emitter Leakage (<br>Collector Leakage (<br>collector Leakage (<br>te Resistance<br>nitter Resistance  | n Voltage<br>n Voltage<br>n Voltage<br>Ditage<br>Current            | $I_{CE} = 2mA$ $R_{GE} = 1K$ $T_{J} = -40 \text{ to}$ $I_{CE} = 10m$ $R_{GE} = 0,$ $T_{J} = -40 \text{ to}$ $I_{CE} = -75r$ $T_{C} = 25^{\circ}C$ $I_{GES} = \pm 2$ $V_{CES} = 25$ See Fig. 1 $V_{EC} = 24V$   | Test Condi         A, $V_{GE} = 0$ ,         Ω, See Fig. 15         D 150°C         IA, $V_{GE} = 0V$ ,         D 150°C         mA, $V_{GE} = 0V$ ,         D 150°C         mA, $V_{GE} = 0V$ ,         D 150°C         mA         50V,         1   | $\frac{T_{C} = 25^{\circ}C}{T_{C} = 150^{\circ}C}$ $T_{C} = 25^{\circ}C$  | 330<br>350<br>30<br>±12<br>-<br>-<br>-<br>-<br>-<br>-<br>- | 363<br>378<br>-<br>±14<br>-<br>-<br>-                     | 390<br>410<br>-<br>25<br>1<br>1<br>40<br>-               | V<br>V<br>V<br>μΑ<br>mA<br>Ω           |
| Symbol<br>Off Sta<br>$3V_{CER}$<br>$3V_{CES}$<br>$3V_{ECS}$<br>$3V_{GES}$<br>CES<br>ECS<br>$R_1$<br>$R_2$<br>On Sta<br>$\sqrt{CE(SAT)}$                                     | te Chara<br>Collector t<br>Collector t<br>Emitter to<br>Gate to Er<br>Collector t<br>Emitter to<br>Series Ga<br>Gate to Er<br>te Chara                | Parameter<br>cteristics<br>o Emitter Breakdow<br>o Emitter Breakdow<br>Collector Breakdown VC<br>o Emitter Leakage (<br>Collector Leakage (<br>Collector Leakage (<br>te Resistance<br>nitter Resistance<br>cteristics  | n Voltage<br>n Voltage<br>Ditage<br>Current<br>Current              | $I_{CE} = 2mA R_{GE} = 1K T_{J} = -40 tr T_{C} = 10m R_{GE} = 0, T_{J} = -40 tr T_{C} = 25^{\circ}C T_{C} = 25^{\circ}C T_{C} = 25^{\circ}C T_{C} = 25 See Fig. 1 V_{EC} = 24 V_{CES} = 25 See Fig. 1 V_{EC} = 24 V_{See} Fig. 1 V_{EC} = 24 V_{CE} = 6A, $ | Test Condi         A, $V_{GE} = 0$ ,         Ω, See Fig. 15         D 150°C         IA, $V_{GE} = 0V$ ,         D 150°C         mA, $V_{GE} = 0V$ ,         D 150°C         mA, $V_{GE} = 0V$ ,         D 150°C         mA         50V,         1   | $T_{C} = 25^{\circ}C$ $T_{C} = 150^{\circ}C$ $T_{C} = 25^{\circ}C$ $T_{C} = 150^{\circ}C$ $T_{C} = 150^{\circ}C$ $T_{C} = 150^{\circ}C$                                     | 330<br>350<br>30<br>±12<br>-<br>-<br>-<br>-<br>10K         | 363<br>378<br>-<br>±14<br>-<br>-<br>-<br>100<br>-         | 390<br>410<br>-<br>25<br>1<br>1<br>40<br>-<br>30K        | V<br>V<br>V<br>μΑ<br>mA<br>Ω<br>Ω      |
| Symbol<br>Dff Sta<br>$3V_{CER}$<br>$3V_{CES}$<br>$3V_{ECS}$<br>$3V_{GES}$<br>CES<br>ECS<br>$R_1$<br>$R_2$<br>Dn Sta   | te Chara<br>Collector t<br>Collector t<br>Emitter to<br>Gate to Er<br>Collector t<br>Emitter to<br>Series Ga<br>Gate to Er<br>te Chara<br>Collector t | Parameter<br>cteristics<br>o Emitter Breakdow<br>o Emitter Breakdow<br>Collector Breakdow<br>nitter Breakdown Vo<br>o Emitter Leakage (<br>Collector Leakage (<br>collector Leakage (<br>te Resistance<br>nitter Resistance<br>cteristics<br>o Emitter Saturation | n Voltage<br>n Voltage<br>oltage<br>Current<br>Current<br>n Voltage | $I_{CE} = 2mA$ $R_{GE} = 1K$ $T_{J} = -40 \text{ to}$ $I_{CE} = 10m$ $R_{GE} = 0,$ $T_{J} = -40 \text{ to}$ $I_{CE} = -75r$ $T_{C} = 25^{\circ}C$ $I_{GES} = \pm 22$ $V_{CES} = 25$ See Fig. 1 $V_{EC} = 24V$ See Fig. 1 $I_{CE} = 6A, V$ $I_{CE} = 10A$   | Test Condi<br>A, $V_{GE} = 0$ ,<br>Ω, See Fig. 15<br>o 150°C<br>A, $V_{GE} = 0V$ ,<br>o 150°C<br>mA, $V_{GE} = 0V$ ,<br>c<br>mA<br>50V,<br>11<br>/,<br>1<br>/<br>(GE = 4V,  | $T_{C} = 25^{\circ}C$ $T_{C} = 150^{\circ}C$ $T_{C} = 25^{\circ}C$ $T_{C} = 150^{\circ}C$ $T_{C} = 150^{\circ}C$ $T_{C} = 150^{\circ}C,$ See Fig. 3 $T_{C} = 150^{\circ}C,$ | 330<br>350<br>±12<br>-<br>-<br>-<br>10K                    | 363<br>378<br>-<br>±14<br>-<br>-<br>-<br>100<br>-<br>1.14 | 390<br>410<br>-<br>25<br>1<br>1<br>40<br>-<br>30K<br>1.4 | V<br>V<br>V<br>μΑ<br>mA<br>Ω<br>Ω<br>Ω |

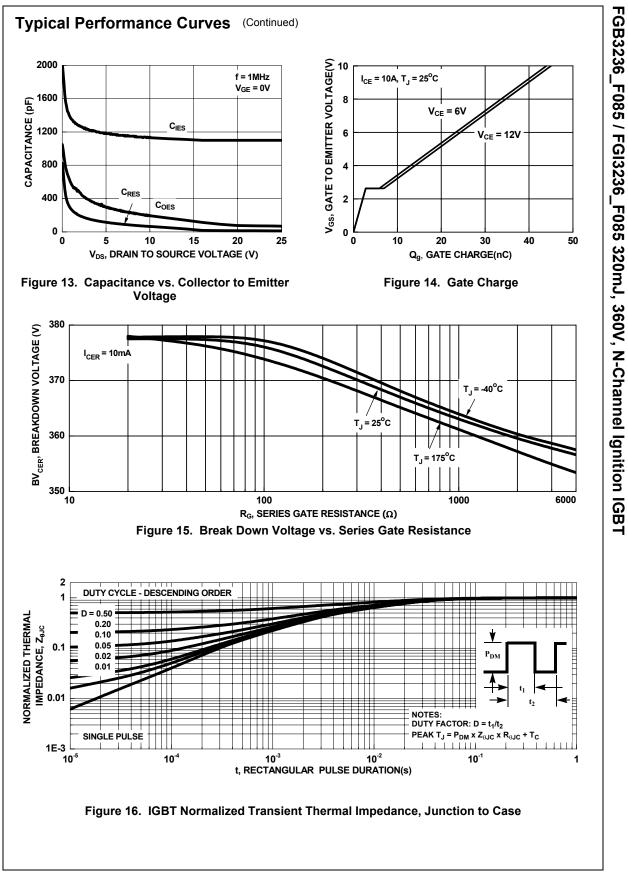
FGB3236\_F085 / FGI3236\_F085 320mJ, 360V, N-Channel Ignition IGBT

| Q <sub>G(ON)</sub> 0           V <sub>GE</sub> (TH)         0           V <sub>GEP</sub> 0           Switchir         0           t <sub>d</sub> (ON)R         0           t <sub>rR</sub> 0           t <sub>d</sub> (OFF)L         0           t <sub>fL</sub> 0 | c Characteristics<br>Gate Charge<br>Gate to Emitter Threshold Voltage<br>Gate to Emitter Plateau Voltage<br>ng Characteristics<br>Current Turn-On Delay Time-Resistive<br>Current Rise Time-Resistive<br>Current Turn-Off Delay Time-Inductive | $I_{CE} = 10A, V_{CE} = 12V,$<br>$V_{GE} = 5V, See Fig.14$<br>$I_{CE} = 1mA, V_{CE} = V_{GE},$<br>See Fig. 10<br>$V_{CE} = 12V, I_{CE} = 10A$<br>$V_{CE} = 14V, R_L = 1\Omega$<br>$V_{GE} = 5V, R_G = 1K\Omega$ | $T_{\rm C} = 25^{\rm o}{\rm C}$<br>$T_{\rm C} = 150^{\rm o}{\rm C}$ | -<br>1.3<br>0.75<br>- | 20<br>1.6<br>1.1<br>2.6 | -<br>2.2<br>1.8 | nC<br>V |
|--|--|---|---|-----------------------|-------------------------|-----------------|---------|
| V <sub>GE(TH)</sub> 0           V <sub>GEP</sub> 0           Switchir         0           t <sub>d(ON)R</sub> 0           t <sub>rR</sub> 0           t <sub>d(OFF)L</sub> 0           t <sub>fL</sub> 0   | Gate to Emitter Threshold Voltage<br>Gate to Emitter Plateau Voltage<br>ng Characteristics<br>Current Turn-On Delay Time-Resistive<br>Current Rise Time-Resistive  | $V_{GE} = 5V$ , See Fig.14<br>$I_{CE} = 1mA$ , $V_{CE} = V_{GE}$ ,<br>See Fig. 10<br>$V_{CE} = 12V$ , $I_{CE} = 10A$<br>$V_{CE} = 14V$ , $R_{L} = 1\Omega$<br>$V_{GE} = 5V$ , $R_{G} = 1K\Omega$                |   | 1.3<br>0.75           | 1.6<br>1.1              | 2.2<br>1.8      |         |
| V <sub>GEP</sub> (           Switchir         (           t <sub>d</sub> (ON)R         (           t <sub>rR</sub> (           t <sub>d</sub> (OFF)L         (           t <sub>fL</sub> (   | Gate to Emitter Plateau Voltage<br>ng Characteristics<br>Current Turn-On Delay Time-Resistive<br>Current Rise Time-Resistive   | See Fig. 10<br>$V_{CE}$ = 12V, $I_{CE}$ = 10A<br>$V_{CE}$ = 14V, $R_L$ = 1 $\Omega$<br>$V_{GE}$ = 5V, $R_G$ = 1K $\Omega$   |   | 0.75                  | 1.1                     | 1.8             | v       |
| Switchir $t_{d(ON)R}$ $t_{rR}$ $t_{rR}$ $t_{d(OFF)L}$ $t_{fL}$   | ng Characteristics<br>Current Turn-On Delay Time-Resistive<br>Current Rise Time-Resistive  | V <sub>CE</sub> = 14V, R <sub>L</sub> = 1Ω<br>V <sub>GE</sub> = 5V, R <sub>G</sub> = 1KΩ  |   | -                     | 2.6                     | -               |         |
| $t_{d(ON)R}$ (<br>$t_{rR}$ (<br>$t_{d(OFF)L}$ (<br>$t_{fL}$ (  | Current Turn-On Delay Time-Resistive<br>Current Rise Time-Resistive  | $V_{GE}$ = 5V, $R_G$ = 1K $\Omega$  |   |                       |                         | _               | V       |
| t <sub>rR</sub> (<br>t <sub>d(OFF)L</sub> (<br>t <sub>fL</sub> (   | Current Rise Time-Resistive  | $V_{GE}$ = 5V, $R_G$ = 1K $\Omega$  |   |                       |                         |                 |         |
| t <sub>d(OFF)L</sub> (   |  |   |   | -                     | 0.65                    | 4               | μS      |
| t <sub>fL</sub>  | Current Turn-Off Delay Time-Inductive  | T <sub>J</sub> = 25 <sup>o</sup> C, See Fig.12  |   | -                     | 1.7                     | 7               | μS      |
|  |  | V <sub>CE</sub> = 300V, L = 500µHy,   |   | -                     | 5.4                     | 15              | μS      |
| SCIS S   | Current Fall Time-Inductive  | V <sub>GE</sub> = 5V,  R <sub>G</sub> = 1KΩ<br>T <sub>J</sub> = 25 <sup>o</sup> C, See Fig.12   |   | -                     | 1.64                    | 15              | μS      |
|  | Self Clamped inductive Switching   | $T_J = 25^{\circ}C, L = 3.0mHy, I_{CE}$<br>$R_G = 1K\Omega, V_{GE} = 5V, See$   |   | -                     | -                       | 320             | mJ      |
| Thermal  | I Characteristics  |   |   |                       |                         |                 |         |
| R <sub>0JC</sub> T   | Thermal Resistance Junction to Case  | All Packages  |   | _                     | _                       | 0.8             | °C/W    |
|  |  |   |   |                       |                         |                 |         |



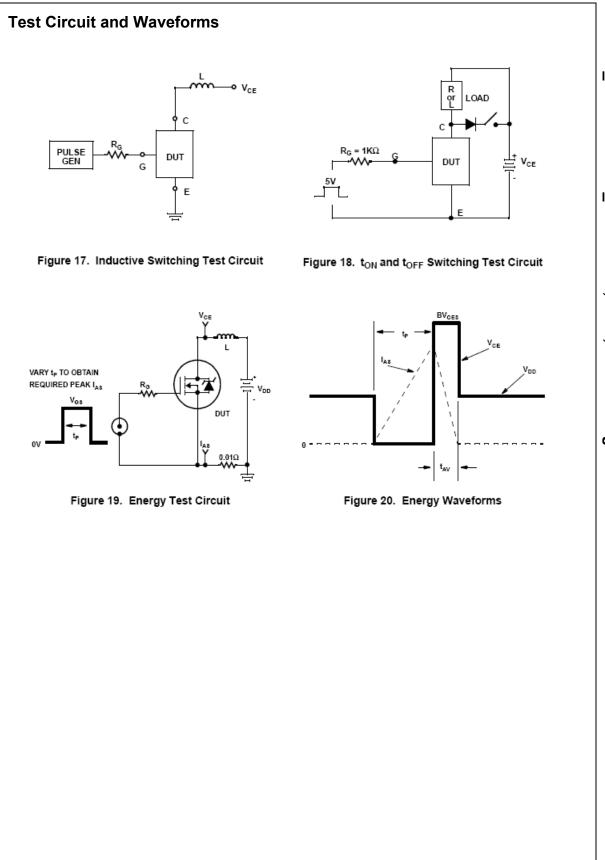


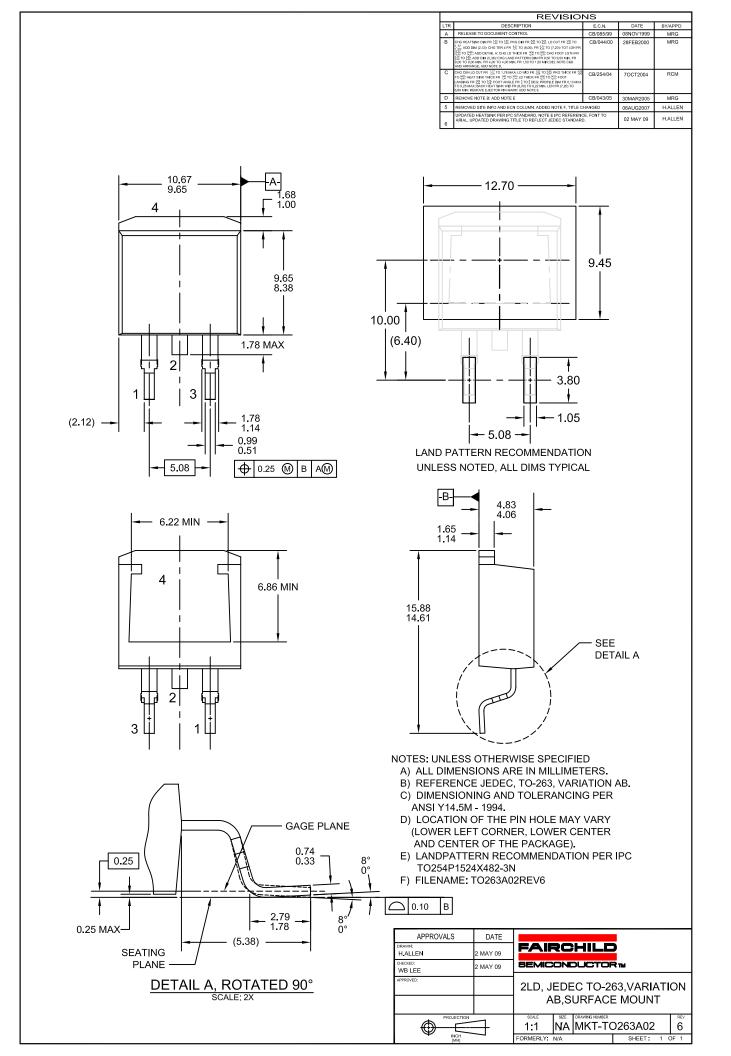
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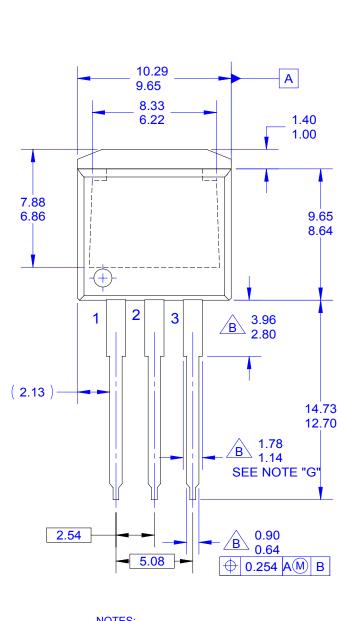


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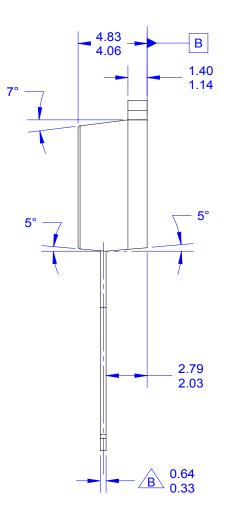




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A. EXCEPT WHERE NOTED CONFORMS TO TO262 JEDEC VARIATION AA. B DOES NOT COMPLY JEDEC STD. VALUE. C. ALL DIMENSIONS ARE IN MILLIMETERS. D. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR PROTRUSIONS. E. DIMENSION AND TOLERANCE AS PER ANSI V14 5-1994 F. LOCATION OF PIN HOLE MAY VARY (LOWER LEFT CORNER, LOWER CENTER AND CENTER OF PACKAGE)
G. MAXIMUM WIDTH FOR F102 DEVICE = 1.35 MAX. H. DRAWING FILE NAME: TO262A03REV5



|                           | DATE      |           |          |              |          |      |  |
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| PROJECTION                |           | SCALE     | SIZE     | DRAWING NUMB |          | REV  |  |
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